

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10628822	WALKER ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Lee, Siu M	2611

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
370	323, 334	10/31/2006	Siu M. Lee
710	38	10/31/2006	Siu M. Lee
455	3.01,3.02,3.03,3.04,7,427,428,12.1,181.1,171.1,178.1,18 6,191.1,456.1,457,414.1,161.2,161.3,166.2,184.1,419,34 5	10/31/2006	Siu M. Lee
710	38	4/27/2007	Siu M. Lee
375	132-137	4/27/2007	Siu M. Lee
455	3.01,7,427,3.02,3.03,428,12.1,3.04,3.06,556,181.1,171.1 ,178.1,186.1,191.1,193.1,193.2,132,184,187,456.1,457,4 14.1,419,345,456.3,20,74,18,66,45,6,3,4,1,4,2,103	4/27/2007	Siu M. Lee
370	316,330,478,132,328,329,335-338,340-342	4/27/2007	Siu M. Lee

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST	10/25/2006	Siu M. Lee
consult primary examiner of 370 (John Pezzlo)	10/27/2006	Siu M. Lee
Discuss the application with SPE (Chieh Fan)	10/30/2006	Siu M. Lee
EAST	4/27/2007	Siu M. Lee
Discuss application and amendment with Chieh Fan	4/27/2007	Siu M. Lee
EAST	10/17/2007	Siu M. Lee
Discuss the RCE with Chieh Fan	10/17/2007	Siu M. Lee

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>